



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No.09/905,320
Filing Date July 13, 2001
Inventor Cem Basceri et al.
Assignee Micron Technology, Inc.
Group Art Unit 1762
Examiner Eric B. Fuller
Attorney's Docket No.MI22-1657
Title: Chemical Vapor Deposition Methods of Forming Barium Strontium Titanate
Comprising Dielectric Layers, Including Such Layers Having a Varied
Concentration of Barium and Strontium Within the Layer

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT


References - See Attached Form PTO-1449


In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. Copies of the cited art are attached hereto. No admission is made regarding whether all the submitted references are prior art.

This Supplemental Information Disclosure Statement is being filed before the mailing of a first office action after the filing of a request for continued examination. Therefore, no fee is believed to be required. However, in the event that a fee is required for filing this Supplemental Information Disclosure Statement, please charge the fee specified under 37 C.F.R. § 1.17(p) to Deposit Account No. 23-0925.

Respectfully submitted,

Dated: 1-9-04

By: 
Mark S. Matkin
Reg. No. 32,268

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| Form PTO-1449 | | U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE | | ATTY. DOCKET NO. MI22-1657 | | SERIAL NO. 09/905,320 | |
|  LIST OF ART CITED BY APPLICANT <small>(Use several sheets if necessary)</small> | | | | APPLICANT: MI22-1657 | | | |
| | | | | FILING DATE July 13, 2001 | | GROUP 1762 | |
| U.S. PATENT DOCUMENTS | | | | | | | |
| *Examiner's Initials | | Document Number | Date | Name | Class | Subclass | Filing Date If Appropriate |
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| | | Document Number | Date | Country | Class | Subclass | Translation |
| | | | | | | | Yes No |
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| | AK | | | | | | |
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| OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.) | | | | | | | |
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